

Appl. No. 10/662,643
Amdt. dated April 25, 2005
Reply to Office action of January 25, 2005

Amendments to the Specification:

Please replace the Abstract with the following amended Abstract:

ABSTRACT

A method for determining the memory element values is disclosed. In some embodiments the method may include: selecting a column of interest containing a desired memory element, disabling the desired memory element, measuring a first current provided to the column of interest, adjusting measurement circuitry to compensate for skew introduced by undesired memory elements, enabling the desired memory elements, and measuring a second current provided to the column of interest.